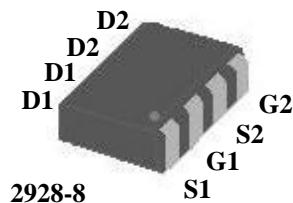




- ▼ Capable of 2.5V gate drive
- ▼ Lower on-resistance
- ▼ Surface mount package
- ▼ RoHS compliant

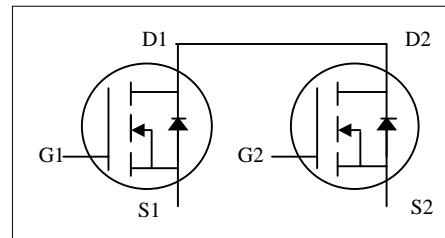


$BV_{DSS}$	30V
$R_{DS(ON)}$	40mΩ
$I_D$	4.8A

## Description

Advanced Power MOSFETs utilized advanced processing techniques to achieve the lowest possible on-resistance, extremely efficient and cost-effectiveness device.

The 2928-8 J-lead package provides good on-resistance performance and space saving like TSOP-6.



## Absolute Maximum Ratings

Symbol	Parameter	Rating	Units
$V_{DS}$	Drain-Source Voltage	30	V
$V_{GS}$	Gate-Source Voltage	$\pm 12$	V
$I_D @ T_A = 25^\circ C$	Continuous Drain Current <sup>3</sup>	4.8	A
$I_D @ T_A = 70^\circ C$	Continuous Drain Current <sup>3</sup>	3.8	A
$I_{DM}$	Pulsed Drain Current <sup>1</sup>	20	A
$P_D @ T_A = 25^\circ C$	Total Power Dissipation	1.39	W
	Linear Derating Factor	0.01	W/°C
$T_{STG}$	Storage Temperature Range	-55 to 150	°C
$T_J$	Operating Junction Temperature Range	-55 to 150	°C

## Thermal Data

Symbol	Parameter	Value	Unit
$R_{thj-a}$	Thermal Resistance Junction-ambient <sup>3</sup>	Max. 90	°C/W



## Electrical Characteristics @ $T_j=25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$V_{\text{GS}}=0\text{V}$ , $I_D=250\mu\text{A}$	30	-	-	V
$\Delta \text{BV}_{\text{DSS}}/\Delta T_j$	Breakdown Voltage Temperature Coefficient	Reference to $25^\circ\text{C}$ , $I_D=1\text{mA}$	-	0.02	-	V/ $^\circ\text{C}$
$R_{\text{DS(ON)}}$	Static Drain-Source On-Resistance <sup>2</sup>	$V_{\text{GS}}=10\text{V}$ , $I_D=5\text{A}$	-	-	32	$\text{m}\Omega$
		$V_{\text{GS}}=4.5\text{V}$ , $I_D=4\text{A}$	-	-	40	$\text{m}\Omega$
		$V_{\text{GS}}=2.5\text{V}$ , $I_D=2\text{A}$	-	-	60	$\text{m}\Omega$
$V_{\text{GS(th)}}$	Gate Threshold Voltage	$V_{\text{DS}}=V_{\text{GS}}$ , $I_D=250\mu\text{A}$	0.5	-	1.2	V
$g_{\text{fs}}$	Forward Transconductance	$V_{\text{DS}}=5\text{V}$ , $I_D=4\text{A}$	-	9	-	S
$I_{\text{DSS}}$	Drain-Source Leakage Current ( $T_j=25^\circ\text{C}$ )	$V_{\text{DS}}=30\text{V}$ , $V_{\text{GS}}=0\text{V}$	-	-	1	$\text{uA}$
	Drain-Source Leakage Current ( $T_j=70^\circ\text{C}$ )	$V_{\text{DS}}=24\text{V}$ , $V_{\text{GS}}=0\text{V}$	-	-	10	$\text{uA}$
$I_{\text{GSS}}$	Gate-Source Leakage	$V_{\text{GS}}=\pm 12\text{V}$	-	-	$\pm 100$	nA
$Q_g$	Total Gate Charge <sup>2</sup>	$I_D=4\text{A}$	-	3	5	nC
$Q_{\text{gs}}$	Gate-Source Charge		-	1.3	-	nC
$Q_{\text{gd}}$	Gate-Drain ("Miller") Charge		-	4	-	nC
$t_{\text{d(on)}}$	Turn-on Delay Time <sup>2</sup>	$V_{\text{DS}}=15\text{V}$	-	10	-	ns
$t_r$	Rise Time		-	11	-	ns
$t_{\text{d(off)}}$	Turn-off Delay Time		-	17	-	ns
$t_f$	Fall Time	$R_G=3.3\Omega$ , $V_{\text{GS}}=5\text{V}$	-	5	-	ns
$C_{\text{iss}}$	Input Capacitance	$V_{\text{GS}}=0\text{V}$	-	480	770	pF
$C_{\text{oss}}$	Output Capacitance	$V_{\text{DS}}=25\text{V}$	-	90	-	pF
$C_{\text{rss}}$	Reverse Transfer Capacitance		-	70	-	pF
$R_g$	Gate Resistance	$f=1.0\text{MHz}$	-	1.5	2.3	$\Omega$

## Source-Drain Diode

Symbol	Parameter	Test Conditions	Min.	Typ.	Max.	Units
$V_{\text{SD}}$	Forward On Voltage <sup>2</sup>	$I_S=1.1\text{A}$ , $V_{\text{GS}}=0\text{V}$	-	-	1.3	V
$t_{\text{rr}}$	Reverse Recovery Time	$I_S=4\text{A}$ , $V_{\text{GS}}=0\text{V}$ ,	-	18	-	ns
$Q_{\text{rr}}$	Reverse Recovery Charge	$dI/dt=100\text{A}/\mu\text{s}$	-	10	-	nC

## Notes:

- 1.Pulse width limited by Max. junction temperature.
- 2.Pulse width  $\leq 300\mu\text{s}$ , duty cycle  $\leq 2\%$ .
- 3.Surface mounted on 1 in<sup>2</sup> copper pad of FR4 board , t  $\leq 5\text{sec}$  ;  $155^\circ\text{C}/\text{W}$  at steady state.

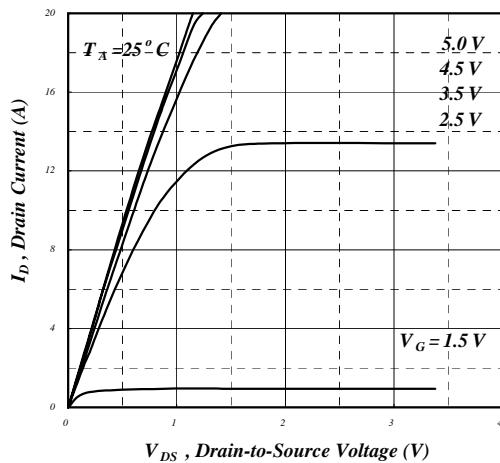


Fig 1. Typical Output Characteristics

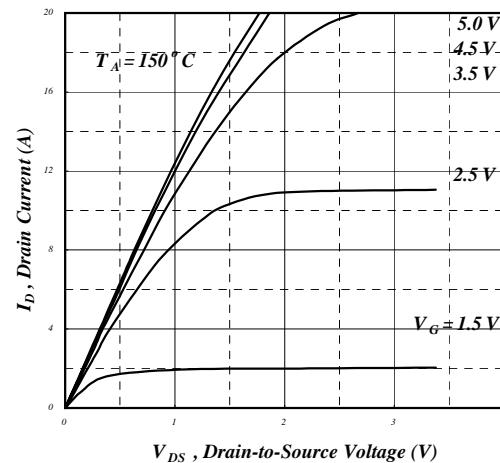


Fig 2. Typical Output Characteristics

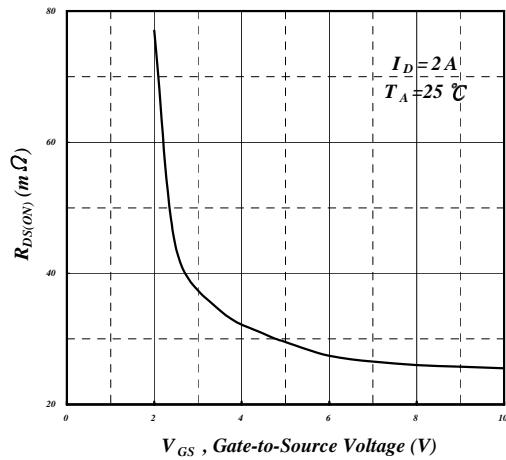


Fig 3. On-Resistance v.s. Gate Voltage

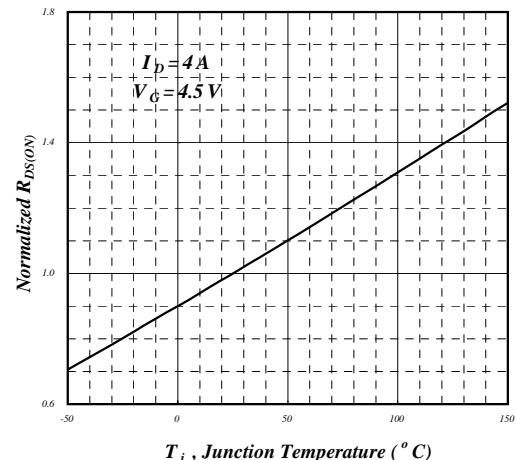


Fig 4. Normalized On-Resistance v.s. Junction Temperature

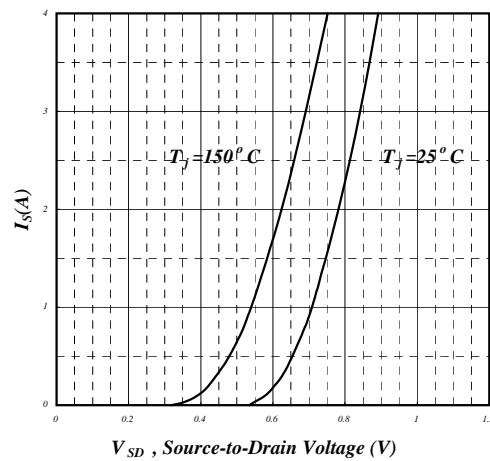


Fig 5. Forward Characteristic of Reverse Diode

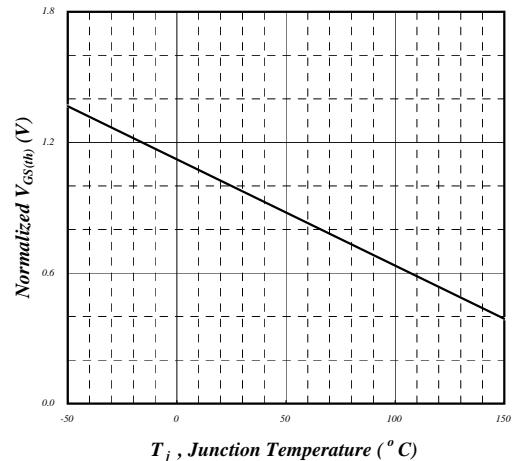


Fig 6. Gate Threshold Voltage v.s. Junction Temperature

